

Search Notes**Application/Control No.**

09/975,912

Examiner

Afsar M. Qureshi

Applicant(s)/Patent under Reexamination

CHEN ET AL.

Art Unit

2667

SEARCHED

Class	Subclass	Date	Examiner
370	310.2	12/1/2005	AQ
	328		
	329		
	331		
	332		
	352		
	401		
	428		
455	442		
	445		
	422		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST/WEST	12/1/2005	AQ
IEEE/FAST		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
Interference search included			